



Certificate of Analysis

ULTRAGrade™ Solution
Silica ICP Standard
1000 µg/mL

Catalog Number: ICP-014A
Lot Number: CL-5273
Lot Issue Date: 12/19/2014
Expiration Date: 01/31/2022

Starting Material: Silicon dioxide
Starting Material Purity: 99.998%
Starting Material Lot #: RM09509
Matrix: Dilute sodium hydroxide in low TOC water (< 50 ppb)
Atomic Weight SiO₂: 60.09

Certified Value: 1000 ± 2 µg/mL

This Certified Reference Material (CRM) was manufactured and verified in accordance with ULTRA's ISO 9001 registered quality system. The analyte concentration(s) were prepared and verified by an ISO Guide 34 / ISO 17025 accredited laboratory, and compared to calibration standards independently prepared using NIST SRM(s). The certified value and uncertainty value at the 95% confidence level for each analyte is determined gravimetrically.

Classical Wet Assay Method: Theoretical, based on gravimetric measurements

Confirmation by Inductively Coupled Plasma Spectroscopy (ICP / ICP/MS) vs. NIST SRM 3150

ULTRA uses purified acids, 18 megohm double deionized water, calibrated Class A glassware & meticulously cleaned bottles in the manufacturing of ULTRAGrade standards. Balances used in the manufacturing of this standard are calibrated with weights traceable to NIST in compliance with ANSI/NCCL Z-540-1 and ISO 9001.

Trace Metallic Impurities in Solution Standard in µg/mL:

| | | | |
|----------------|----------------|----------------|----------------|
| * Al <0.005 ND | * Ga <0.005 ND | n Nb | n S |
| * Sb <0.005 ND | n Ge | n Os | n Ta |
| * As <0.005 ND | n Au | * Pd <0.005 ND | n Te |
| * Ba <0.005 ND | n Hf | s P | n Tb |
| * Be <0.005 ND | n Ho | * Pt <0.005 ND | n Tl <0.005 ND |
| * Bi <0.005 ND | * In <0.005 ND | * K <0.005 ND | n Th |
| * B <0.005 ND | n Ir | n Pr | n Tm |
| * Cd <0.005 ND | * Fe <0.005 ND | n Re | * Sn <0.005 ND |
| * Ca <0.005 ND | * La <0.005 ND | n Rh | * Ti <0.005 ND |
| n Ce | * Pb <0.005 ND | n Rb | n W |
| n Cs | * Li <0.005 ND | n Ru | n U |
| * Cr <0.005 ND | n Lu | n Sm | * V <0.005 ND |
| * Co <0.005 ND | * Mg <0.005 ND | n Sc | n Yb |
| * Cu <0.005 ND | * Mn <0.005 ND | * Se <0.005 ND | n Y |
| n Dy | * Hg <0.005 ND | s Si | * Zn <0.005 ND |
| * Er <0.005 ND | * Mo <0.005 ND | * Ag <0.005 ND | n Zr |
| * Eu <0.005 ND | n Nd | * Na <0.005 ND | |
| * Gd <0.005 ND | * Ni <0.005 ND | * Sr <0.005 ND | |

* - element checked for
ND - not detected

I - spectral interference
D - detected

n - not checked for
s - solution standard element

Density of Solution (measured at 20.00°C ± 0.05°C): 1.0016 g/mL



ISO 17025:2005
Accredited
A2LA
Cert. No. 0851.01

ISO 9001:2000
Registered
TUV USA, Inc.
Cert. No. 06-1004

William J. Leary
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